TOSHIBA FIELD EFFECT TRANSISTOR SILICON P CHANNEL MOS TYPE (π-MOSV)

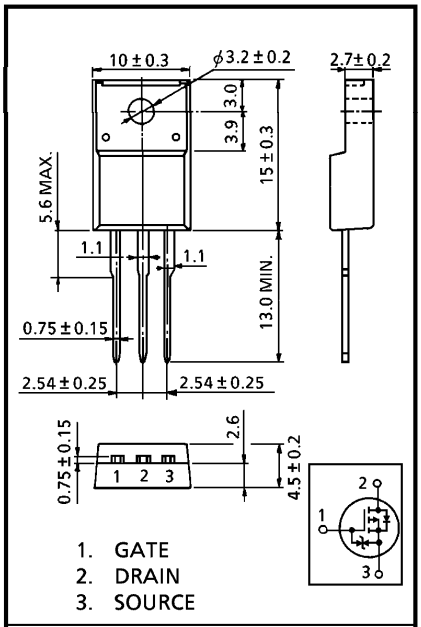
2SJ512

HIGH SPEED, HIGH CURRENT SWITCHING APPLICATIONS

CHOPPER REGULATOR, DC-DC CONVERTER AND MOTOR DRIVE APPLICATIONS

INDUSTRIAL APPLICATIONS

Unit in mm



JEDEC	—
EIAJ	SC-67
TOSHIBA	2-10R1B

- Low Drain-Source ON Resistance : $R_{DS\,(ON)} = 1.0\ \Omega$ (Typ.)
- High Forward Transfer Admittance : $|Yfs| = 3.7$ S (Typ.)
- Low Leakage Current : $I_{DSS} = -100\ \mu A$ (Max.) ($V_{DS} = -250$ V)
- Enhancement-Mode : $V_{th} = -1.5 \sim -3.5$ V ($V_{DS} = -10$ V, $I_D = -1$ mA)

MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC		SYMBOL	RATING	UNIT
Drain-Source Voltage		V_{DSS}	−250	V
Drain-Gate Voltage ($R_{GS} = 20\ k\Omega$)		V_{DGR}	−250	V
Gate-Source Voltage		V_{GSS}	±20	V
Drain Current	DC	I_D	−5	A
	Pulse	I_{DP}	−20	A
Drain Power Dissipation (Tc = 25°C)		P_D	30	W
Single Pulse Avalanche Energy**		E_{AS}	155	mJ
Avalanche Current		I_{AR}	−5	A
Repetitive Avalanche Energy*		E_{AR}	3.0	mJ
Chanel Temperature		T_{ch}	150	°C
Storage Temperature Range		T_{stg}	−55~150	°C

THERMAL CHARACTERISTICS

CHARACTERISTIC	SYMBOL	MAX.	UNIT
Thermal Resistance, Chanel To Case	$R_{th\,(ch\text{-}c)}$	4.16	°C / W
Thermal Resistance, Chanel to Ambient	$R_{th\,(ch\text{-}a)}$	62.5	°C / W

Note ;

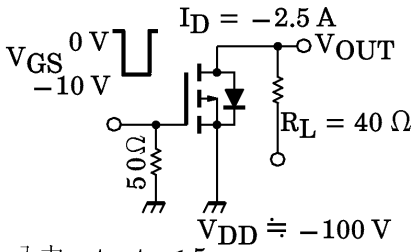
* Repetitive rating ; Pulse Width Limited by Max. junction temperature.

** $V_{DD} = -50$ V, $T_{ch} = 25$°C (initial), L = 10.5 mH, $R_G = 25\ \Omega$, $I_{AR} = -5$ A

This transistor is an electrostatic sensitive device.
Please handle with caution.

961001EAA1

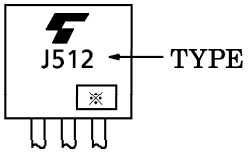
ELECTRICAL CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC		SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Gate Leakage Current		I_{GSS}	$V_{GS} = \pm 16V$, $V_{DS} = 0$ V	—	—	±10	μA
Drain Cut-off Current		I_{DSS}	$V_{DS} = -250$ V, $V_{GS} = 0$ V	—	—	−100	μA
Drain-Source Breakdown Voltage		$V_{(BR)\,DSS}$	$I_D = -10$ mA, $V_{GS} = 0$V	−250	—	—	V
Gate Threshold Voltage		V_{th}	$V_{DS} = -10$ V, $I_D = -1$ mA	−1.5	—	−3.5	V
Drain-Source ON Resistance		$R_{DS\,(ON)}$	$V_{GS} = -10$ V, $I_D = -2.5$ A	—	1.0	1.25	Ω
Forward Transfer Admittance		$\|Yfs\|$	$V_{DS} = -10$ V, $I_D = -2.5$ A	1.8	3.7	—	S
Input Capacitance		C_{iss}	$V_{DS} = -10$ V, $V_{GS} = 0$ V, f = 1MHz	—	800	—	pF
Reverse Transfer Capacitance		C_{rss}		—	80	—	
Output Capacitance		C_{oss}		—	250	—	
Switching Time	Rise Time	t_r		—	16	—	ns
	Turn-on Time	t_{on}		—	35	—	
	Fall Time	t_f		—	9	—	
	Turn-off Time	t_{off}		—	70	—	
Total Gate Charge (Gate-Source Plus Gate-Drain)		Q_g	$V_{DD} \fallingdotseq -200$ V, $V_{GS} = -10$ V, $I_D = -5$ A	—	22	—	nC
Gate-Source Charge		Q_{gs}		—	14	—	
Gate-Drain ("Miller") Charge		Q_{gd}		—	8	—	

SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Continuous Drain Reverse Current	I_{DR}	—	—	—	−5	A
Pulse Drain Reverse Current	I_{DRP}	—	—	—	−20	A
Diode Forward Voltage	V_{DSF}	$I_{DR} = -5$ A, $V_{GS} = 0$ V	—	—	2.0	V
Reverse Recovery Time	t_{rr}	$I_{DR} = -5$ A, $V_{GS} = 0$ V, $dI_{DR}/dt = 100$ A/μs	—	205	—	ns
Reverse Recovery Charge	Q_{rr}		—	2.1	—	μC

MARKING

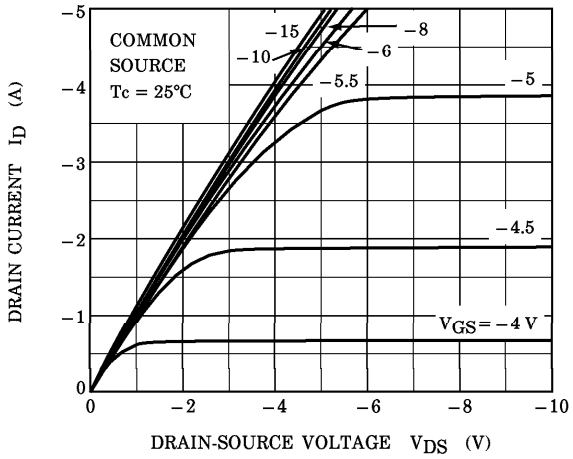


※ Lot Number

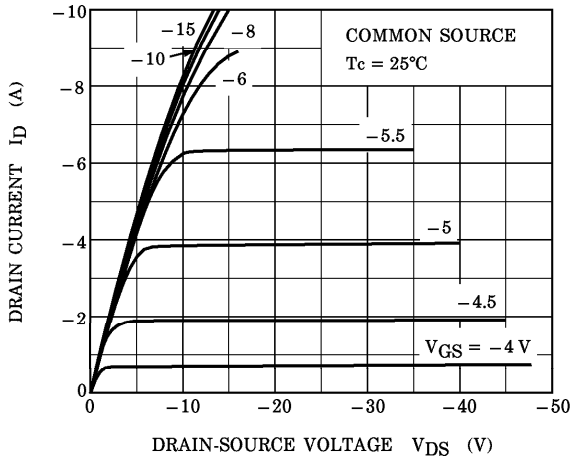
□□ — Month (Starting from Alphabet A)

└— Year (Last Number of the Christian Era)

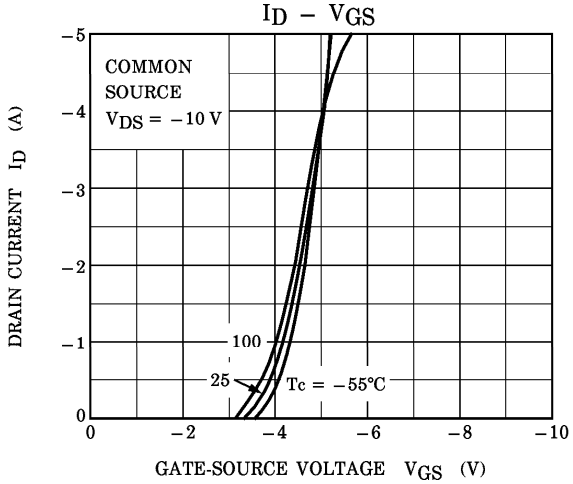
$I_D - V_{DS}$



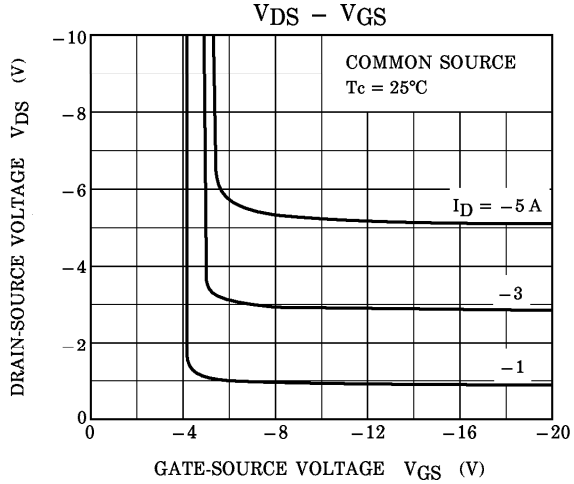
$I_D - V_{DS}$



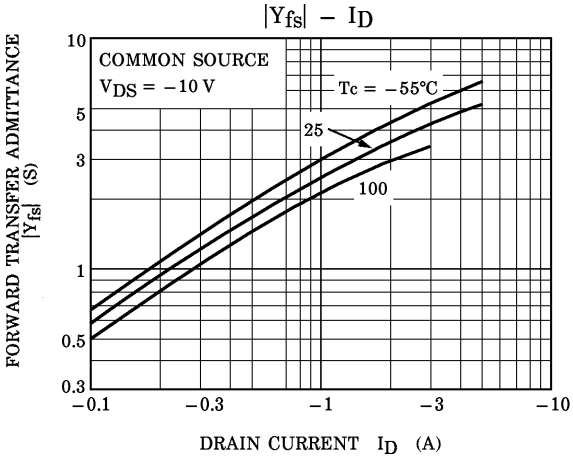
$I_D - V_{GS}$



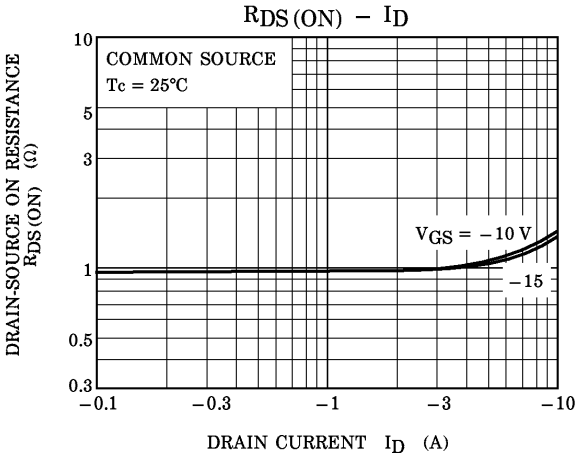
$V_{DS} - V_{GS}$



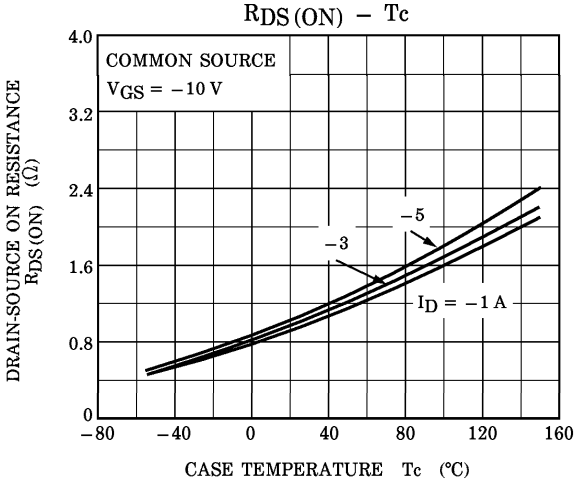
$|Y_{fs}| - I_D$



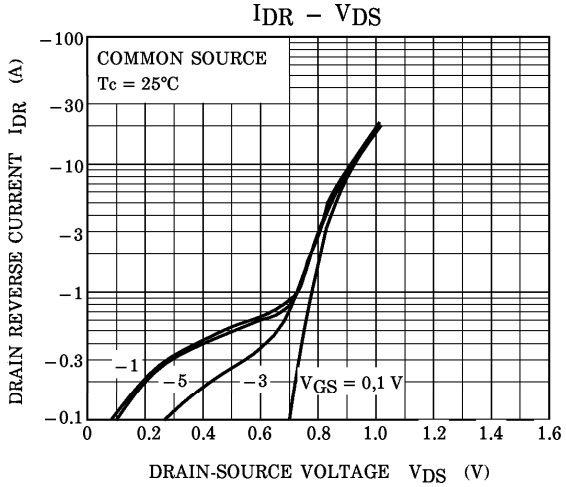
$R_{DS\,(ON)} - I_D$



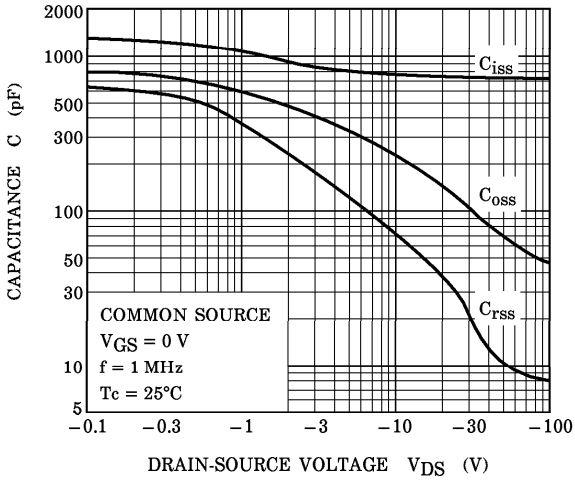
$R_{DS(ON)}$ – Tc



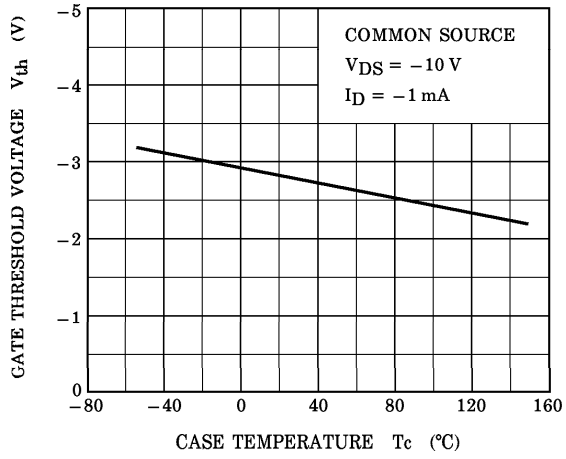
I_{DR} – V_{DS}



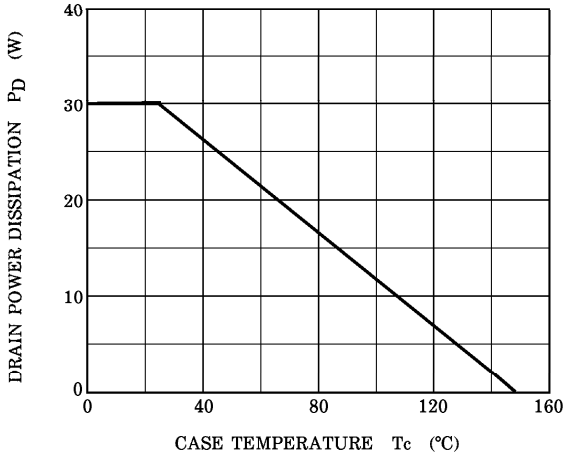
CAPACITANCE – V_{DS}



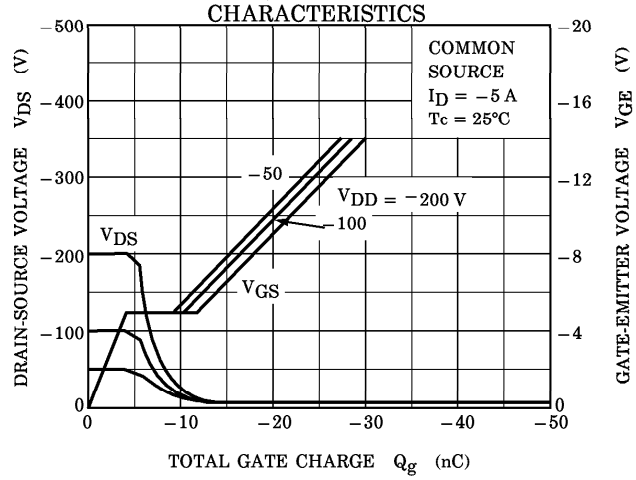
V_{th} – Tc



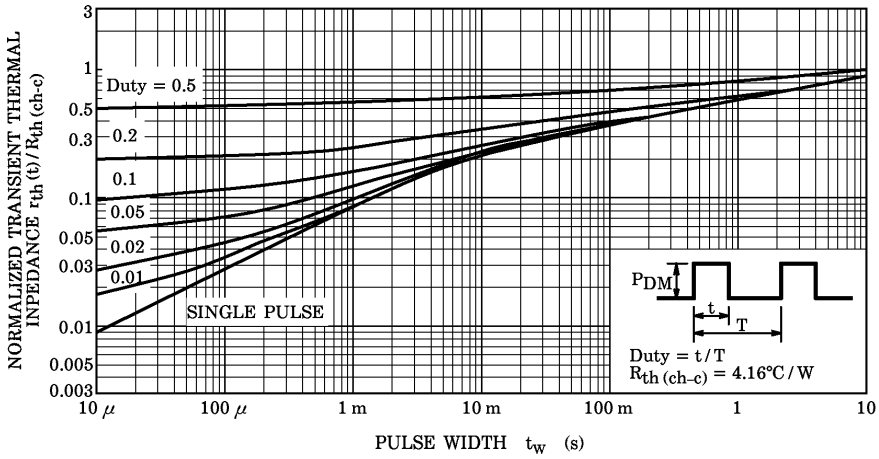
P_D – Tc



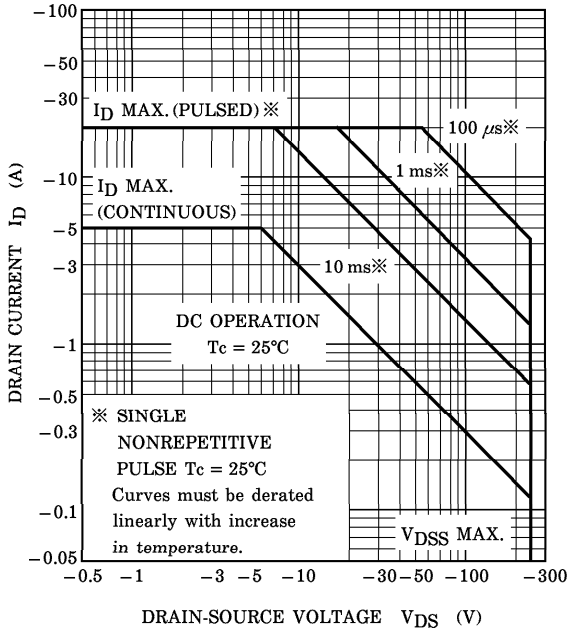
DYNAMIC INPUT / OUTPUT CHARACTERISTICS



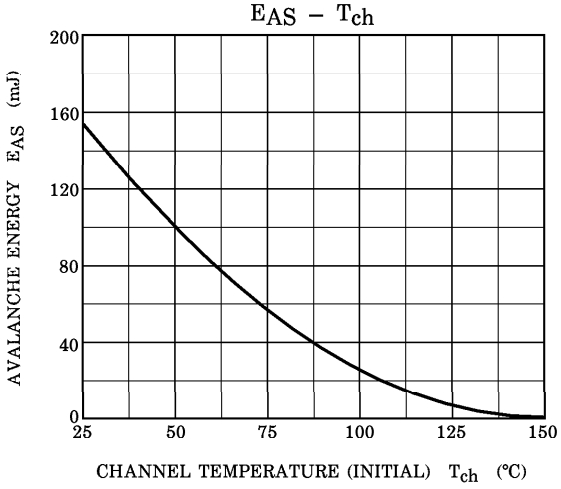
$r_{th} - t_w$

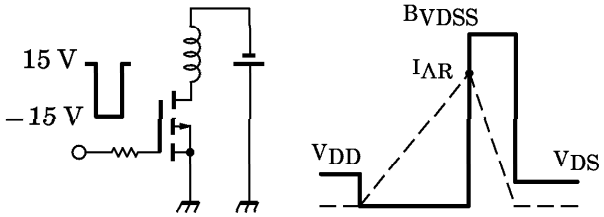


SAFE OPERATING AREA



$E_{AS} - T_{ch}$





TEST CIRCUIT WAVE FORM

Peak $I_{AR} = -5$ A, $R_G = 25\ \Omega$
$V_{DD} = -50$ V, L = 10.5 mH

$$E_{AS} = \frac{1}{2} \cdot L \cdot I^2 \cdot \left(\frac{B_{VDSS}}{B_{VDSS} - V_{DD}} \right)$$